High-order Wavelets for Hierarchical Refinement in Inverse Rendering

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http://nick.feed-back.be/hierarchHighOrderWav/

Problem

It is common to use factored representation of visibility, lighting and BRDF in inverse rendering. Current techniques use Haar wavelets to calculate these triple product integrals efficiently. Haar wavelets are an ideal basis for the piecewise constant visibility function, but suboptimal for the smoother lighting and material functions. How can we leverage compact high-order wavelet bases to improve efficiency, memory consumption and accuracy of an inverse rendering algorithm?

Results

Forward Rendering with high-order wavelets



Quality comparison for two different Leftmost datasets. column: environment map and meshes. Two central columns: rendering with optimal wavelet basis (green) versus Haar basis (red). Rightmost column: Zoomed

- Triple product Haar wavelet integrals for all-frequency relighting^{1,2}
- Hierarchical refinement of reflectance³
- Hierarchical splitting of wavelet coefficients^{4,5,6}

Motivation

Previous Work

- Previous triple product methods only render at low frame rates (< 15 fps) for large models (> 100.000 polygons). If triple product integrals can be efficiently calculated for higher-order wavelets, the reduction in coefficients will reduce the number of calculations, therefore improving performance and memory usage. Some BRDFs can be stored 5x more compactly.
- Current inverse rendering algorithms rely on solving large systems of bilinear equations. We propose a hierarchical refinement algorithm that exploits the tree structure of the wavelet basis. By only splitting at interesting nodes in the hierarchy, large portions of less important coefficients can be skipped.

Overview

Triple product integral

Solving the rendering equation as a triple product integral: $B(x,\omega_o) = \sum_{i} \sum_{i} \sum_{k} V_i \tilde{L}_j \rho_k \int_{\Omega} \Psi_i(\omega_i) \Psi_j(\omega_i) \Psi_k(\omega_i) d\omega_i$



Hierarchical Refinement



images to compare quality. Our method produces better quality with up to 5x reduction in coefficients.

Here, a hierarchical refinement scheme is used to estimate the lighting environment map. Stepby-step, the most interesting coefficients on a certain detail level are added to the sparse wavelet tree, based on a splitting criterium. Reconstructions for both Haar and the smoother Coiflet wavelet bases are shown. Haar has a tendency to introduce disturbing high frequencies around edges.

- 3 factors: V_i visibility, \tilde{L}_i environment map in local frame, ρ_k BRDF
- Preprocess binding coefficients $\int_{\Omega} \Psi_i(\omega_i) \Psi_j(\omega_i) \Psi_k(\omega_i) d\omega_i$
- High-order wavelets have overlapping support \rightarrow more complex tensor



Our method exploits the hierarchical nature and vanishing moments of wavelets, resulting in fast calculation of a sparse tensor.

Hierarchical refinement scheme

The key of this algorithm is only splitting nodes of the wavelet tree that contribute to the solution of the system M:

```
M: initialize system to solve at root node of wavelet tree
repeat
    K: set of possible nodes for refinement
    for k \in K do
       concatenate k to M: M = M | M_k
       if rank(M) \neq full then remove k from K
        end if
   end for
   Solve M for \tilde{L}
until no splits left
```

It is critical to use high-order wavelets for this, as Haar wavelet can only introduce high frequencies which lead to blockiness.

Inverse Rendering



Reconstruction of a temporal face dataset under different lighting conditions. Lighting and materials are estimated with the hierarchical refinement method.

Ray traced occlusion maps, BRDF slices and lighting environment map are combined in the triple product integral calculation.

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